INTERNATIONAL STANDARD

IEC 60738-1

QC 440000 Third edition 2006-04



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INTERNATIONAL STANDARD

IEC 60738-1

QC 440000 Third edition 2006-04

Thermistors – Directly heated positive temperature coefficient –

Part 1:
Generic specification
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PRICE CODE



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

THERMISTORS – DIRECTLY HEATED POSITIVE TEMPERATURE COEFFICIENT –

Part 1: Generic specification

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International Standard IEC 60738-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment.

This third edition cancels and replaces the second edition published in 1998 and constitutes a minor revision. The changes with respect to the previous edition refer to the tables, figures and references.

The text of this standard is based on the following documents:

FDIS	Report on voting
40/1651/FDIS	40/1730/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The QC number that appears on the front cover of this publication is the specification number in the IEC Quality Assessment System for Electronic Components (IECQ).

IEC 60738 consists of the following parts, under the general title *Thermistors – Directly heated positive step-function coefficient*:

Part 1: Generic specification

Part 1-1: Blank detail specification – Current limiting application – Assessment level EZ

Part 1-2: Blank detail specification – Heating element application – Assessment level EZ

Part 1-3: Blank detail specification – Inrush current application – Assessment level EZ

Part 1-4: Blank detail specification – Sensing application – Assessment level EZ

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- · reconfirmed:
- · withdrawn:
- · replaced by a revised edition, or
- · amended.

A bilingual version of this standard may be issued at a later date.

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https://standards.iteh.ax/vx/standards.ec/xx3.a38a3-1774-4717-8c36-71df5ecf135b/iec-60738-1-2006

THERMISTORS – DIRECTLY HEATED POSITIVE TEMPERATURE COEFFICIENT –

Part 1: Generic specification

1 Scope

This part of IEC 60738 describes terms and methods of test for positive step-function temperature coefficient thermistors, insulated and non-insulated types typically made from ferro-electric semi-conductor materials.

It establishes standard terms, inspection procedures and methods of test for use in detail specifications for Qualification Approval and for Quality Assessment Systems for electronic components.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), Letter symbols to be used in electrical technology

IEC 60050 (all parts), International Electrotechnical Vocabulary (IEV)

IEC 60062, Marking codes for resistors and capacitors

https:IEC 60068-1:1988, Environmental testing – Part 1: General and guidance of 135b/iec-60738-1-2006 Amendment 1 (1992)

IEC 60068-2-1:1990, Environmental testing – Part 2: Tests – Tests A: Cold Amendment (1993)

Amendment 2 (1994)

IEC 60068-2-2:1974, Environmental testing – Part 2: Tests – Tests B: Dry heat Amendment 1 (1993)

IEC 60068-2-6, Environmental testing – Part 2: Tests – Test Fc: Vibration (sinusoidal)

IEC 60068-2-11, Environmental testing - Part 2: Tests - Test Ka: Salt mist

IEC 60068-2-13, Environmental testing – Part 2: Tests – Test M: Low air pressure

IEC 60068-2-14:1984, Environmental testing – Part 2: Tests – Test N: Change of temperature Amendment 1 (1986)

IEC 60068-2-20:1979, Environmental testing – Part 2: Tests – Test T: Soldering Amendment 2 (1987)

IEC 60068-2-21, Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices

IEC 60068-2-27, Environmental testing – Part 2: Tests – Test Ea and guidance: Shock

IEC 60068-2-29, Environmental testing – Part 2: Tests – Test Eb and guidance: Bump

IEC 60068-2-30:2005, Environmental testing – Part 2: Tests – Test Db: Damp heat, cyclic (12 h + 12-hour cycle)

IEC 60068-2-45:1980, Environmental testing – Part 2: Tests – Test XA and guidance – Immersion in cleaning solvents

IEC 60068-2-58, Environmental testing — Part 2-58: Tests — Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)

IEC 60068-2-78, Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state

IEC 60294, Measurement of the dimensions of a cylindrical component having two axial terminations

IEC 60410, Sampling plans and procedures for inspection by attributes

IEC 60617 (all parts) [DB]1: Graphical symbols for diagrams

IEC 60717, Method for determination of the space required by capacitors and resistors with unidirectional terminations

IEC 61249-2-7, Materials for printed boards and other interconnecting structures — Part 2-7: Reinforced base materials clad and unclad — Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper clad

IEC 61760-1, Surface mounting technology - Part 1: Standard method for the specification of surface mounting components (SMDs)

IEC QC 001002-3, Rules of Procedure of the IEC Quality Assessment System for Electronic Components (IECQ) — Part 3: Approval procedures

ISO 1000, Stunits and recommendations for the use of their multiples and of certain other units

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

3.1

type

group of components having similar design features and the similarity of whose manufacturing techniques enables them to be grouped together either for qualification approval or for quality conformance inspection

They are generally covered by a single detail specification

NOTE Components described in several detail specifications, may, in some cases, be considered as belonging to the same type but they are generally covered by a single detail specification.

¹ "DB" refers to the IEC on-line database.

3.2

style

variation within a type having specific nominal dimensions and characteristics

3.3

thermistor

thermally sensitive semiconducting resistor which exhibits a significant change in electrical resistance with a change in body temperature

3.4

positive temperature coefficient thermistor

thermistor, the resistance of which increases with its increasing temperature throughout the useful part of its characteristic

3.5

positive step-function temperature coefficient thermistor PTC

thermistor which shows a step-like increase in its resistance when the increasing temperature reaches a specific value

A PTC thermistor will show secondary effects which are to be taken into account

3.6

zero-power resistance

R_{T}

value of the resistance of a PTC thermistor, at a given temperature, under conditions such that the change in resistance due to the internal generation of heat is negligible with respect to the total error of measurement

NOTE Any resistance value of a PTC thermistor is dependent on the value and the mode of the applied voltage (a.c. or d.c.) and, when an a.c. source is used, on the frequency (see 3.8 and 3.9).

3.7

nominal zero-power resistance

ĸn

d.c. resistance value of a thermistor measured at a specified temperature, preferably at 25 °C, with a power discipation low enough that any further decrease in power will result only in a negligible change in resistance. Zero-power resistance may also be measured using a.c. if required by the detail specification

3.8

voltage dependency

secondary effect, exhibiting a decreasing resistance with increasing voltage across the thermistor when measured at a constant body temperature

3.9

frequency dependency

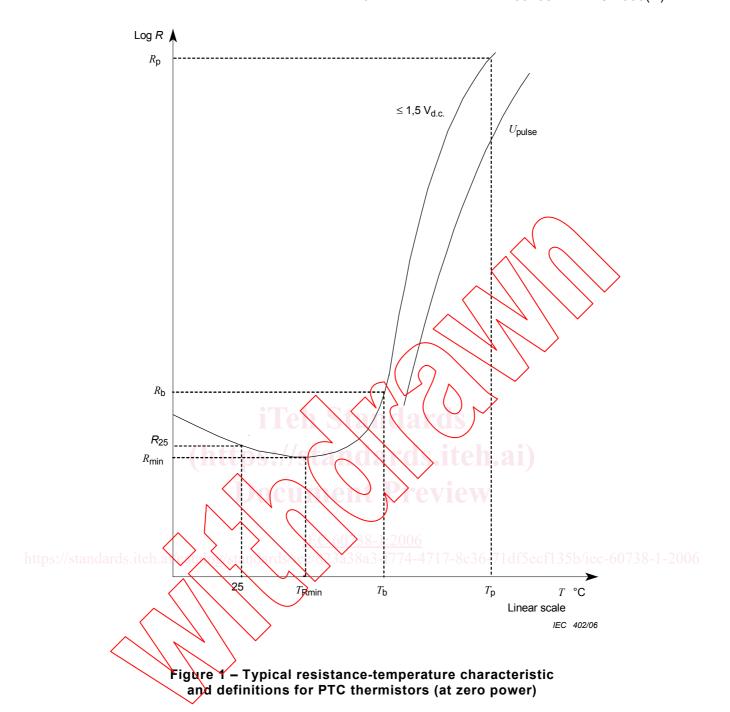
secondary effect exhibiting a substantial decrease of the positive temperature coefficient of the thermistor with increasing frequency

3.10

resistance/temperature characteristics

relationship between the zero-power resistance of a thermistor and the temperature of the thermo-sensitive element when measured under specified reference conditions (see Figure 1)

NOTE PTC thermistors may have more than one resistance/temperature characteristic specified. The zero-power resistance of the resistance/temperature characteristics can be measured using a pulse voltage ($U_{\rm pulse}$) higher than 1,5 V, which is specified in the detail specification. The right curve in Figure 1 shows the typical resistance/temperature characteristic when using the pulse voltage ($U_{\rm pulse}$).



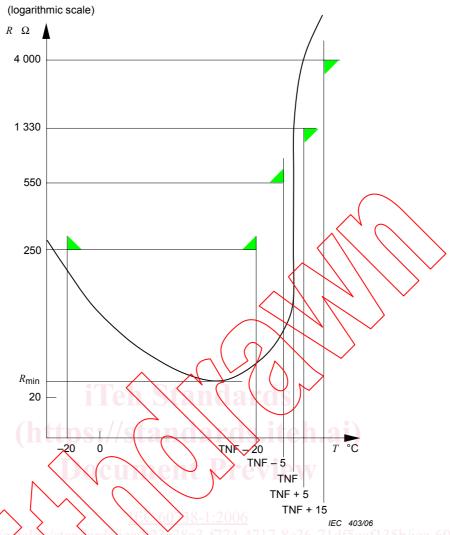
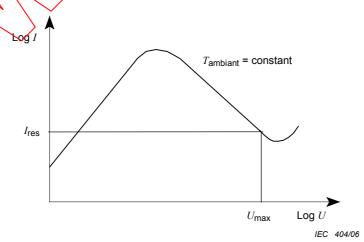


Figure 2 - Typical R-TNF characteristic for PTC thermistors in sensor applications

3.11 current/voltage characteristic

relationship in still air at 25 °C (unless otherwise stated) between the applied voltage (d.c. and/or a c.) at the thermistor terminations and the current under steady-state conditions (see Figure 3)



NOTE 1 $U_{\mbox{max}}$ will be specified by the manufacturer.

NOTE 2 The breakdown voltage is the value beyond which the voltage-handling capability of the thermistor no longer exhibits its characteristic property

Figure 3 - Typical current/voltage characteristic for PTC thermistors

3.12

nominal functioning temperature

nominal temperature at the steep part of the resistance temperature characteristic at which the system controlled by the thermistor is designed to operate

NOTE T_{NF} is exclusively defined for PTC resistors in sensor applications.

switching temperature

temperature at which the step-like function commences

3.14

minimum resistance

minimum value of the zero-power resistance/temperature characteristic (see Figures 1 and 2)

3.15

resistance at switching temperature

value of the zero-power resistance corresponding to the switching temperature defined as $R_{\rm b}$ = $2 \times R_{\text{min}}$. As an alternative definition $R_{\text{b}} = 2 \times R_{25}$ can be used. If this definition is used, this shall be explicitly stated in the detail specification

temperature for minimum resistance

 $T_{\rm Rmin}$ temperature at which $R_{\rm min}$ occurs

3.17

temperature

temperature, higher than $T_{\rm b}$, in the PTC part of the resistance/temperature characteristic for which a minimum value Rp of the zero-power resistance is specified

3.18 resistance

zero-power resistance at temperature $T_{\rm p}$ measured at maximum voltage or a voltage specified in the detail specification and given as a minimum value

NOTE The measurement should be made under such conditions that a change in resistance due to internal generation of heat is negligible with respect to the total error of measurement. The applied voltage and the characteristics of any pulse used should be given in the detail specification; when applying the maximum voltage, the maximum overload current may not be exceeded.

3.19

average temperature coefficient of resistance at a stated voltage

rate of change of resistance with temperature expressed as %/K

It is calculated from the formula:

$$\alpha_{\mathsf{R}} = \frac{100}{(T_{\mathsf{p}} - T_{\mathsf{b}})} \times \ln \frac{R_{\mathsf{p}}}{R_{\mathsf{b}}}$$

where $T_{\rm p}$ exceeds $T_{\rm b}$ by a minimum of 10 K.